

Training Policy for cAFM:

The c-AFM is supported by a staff member Shweta Nair.

1. Initial usage (3 times) maybe done on a service mode to evaluate the utility of the tool for the user & advisor's research.
2. If the advisor then emails the c-AFM staff for training, then only one student from each group can be trained on the Conductive Atomic Force Microscopy (cAFM).
3. Users are requested to submit a new request with their own samples for each training session.
4. Training will comprise of
 - a. 1 demo run
 - b. 2 guided training
 - c. Test

if the student does not pass by a max of 2 tests, then the c-AFM committee will review the case to understand if the student may be allowed for further training/testing or disqualified.